

STTH6112TV

Ultrafast recovery - 1200 V diode

Main product characteristics

I _{F(AV)}	2 x 30 A
V _{RRM}	1200 V
Тj	150° C
V _F (typ)	1.30 V
t _{rr} (typ)	45 ns

Features and benefits

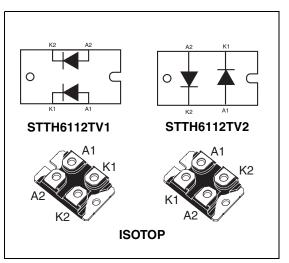
- Ultrafast, soft recovery
- Very low conduction and switching losses
- High frequency and/or high pulsed current operation
- High reverse voltage capability
- High junction temperature
- Insulated package: Electrical insulation = 2500 V_{RMS} Capacitance < 45 pF

Description

The high quality design of this diode has produced a device with low leakage current, regularly reproducible characteristics and intrinsic ruggedness. These characteristics make it ideal for heavy duty applications that demand long term reliability.

Such demanding applications include industrial power supplies, motor control, and similar mission-critical systems that require rectification and freewheeling. These diodes also fit into auxiliary functions such as snubber, bootstrap, and demagnetization applications.

The improved performance in low leakage current, and therefore thermal runaway guard band, is an immediate competitive advantage for this device.



Order codes

Part Number	Marking
STTH6112TV1	STTH6112TV1
STTH6112TV2	STTH6112TV2

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1 Characteristics

Table 1.	Absolute ratings (limiting values per diode at 25° C, unless otherwise specified)
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Symbol		Value	Unit		
V _{RRM}	Repetitive peak reverse voltage	Repetitive peak reverse voltage			V
I _{F(RMS)}	RMS forward current	RMS forward current			А
I _{F(AV)}	Average forward current, $\delta = 0.5$ $T_c = 70^{\circ} C$ per diode			30	А
I _{FRM}	Repetitive peak forward current	$t_p = 5 \ \mu s$, F = 5 kHz sq	300	А	
I _{FSM}	Surge non repetitive forward current	t _p = 10 ms Sinusoidal	250	А	
T _{stg}	Storage temperature range			-65 to + 150	°C
Тj	Maximum operating junction temperature			150	°C

Table 2.Thermal parameters

Symbol	Parameter		Value	Unit
P	Junction to case	Per diode	1.16	
R _{th(j-c)} Ju	Total	0.63	°C/W	
R _{th(c)}	Coupling thermal resistance		0.1	

When the diodes are used simultaneously:

 $\Delta T_{j(diode1)} = P_{(diode1)} \times R_{th(j-c)} (per diode) + P_{(diode2)} \times R_{th(c)}$

Table 3. Static electrical characteristics

Symbol	Parameter	Test conditions		Min.	Тур	Max.	Unit
ا _B ⁽¹⁾	Reverse leakage current	T _j = 25° C				20	μA
'R` ´	neverse leakage current	T _j = 125° C	· V _R = V _{RRM}		15	150	
	V _F ⁽²⁾ Forward voltage drop	T _j = 25° C				2.10	
		T _j = 125° C	I _F = 25 A		1.25	1.90	
V (2)		T _j = 150° C			1.20	1.80	v
VF`		T _j = 25° C				2.25	v
		T _j = 125° C	I _F = 30 A		1.35	2.05	
		$T_j = 150^\circ C$			1.30	1.95	

1. Pulse test: $t_p = 5 \text{ ms}, \delta < 2 \%$

2. Pulse test: t_p = 380 μ s, δ < 2 %

To evaluate the conduction losses use the following equation: P = 1.60 x $I_{F(AV)}$ + 0.012 ${I_F}^2_{(RMS)}$

Symbol	Parameter	Test conditions	Min.	Тур	Max.	Unit
		$\begin{array}{l} I_F=1 \; A, \; dI_F/dt=\text{-50 } A/\mus, \\ V_R=30 \; V, \; T_j=25^\circ \; C \end{array}$			115	
t _{rr}	Reverse recovery time	$I_F = 1 \text{ A, } dI_F/dt = -100 \text{ A/}\mu\text{s},$ $V_R = 30 \text{ V, } T_j = 25^{\circ} \text{ C}$		57	80	ns
	$ I_F = 1 \text{ A, } dI_F/dt = -200 \text{ A}/\mu\text{s}, \\ V_R = 30 \text{ V, } T_j = 25^\circ \text{ C} $		45	65		
I _{RM}	Reverse recovery current	I _F = 30 A, dI _F /dt = -200 A/μs, V _R = 600 V, T _j = 125° C		25	35	А
S	$ \begin{array}{l} \mbox{Softness factor} \\ \mbox{I}_{F} = 30 \mbox{ A, } dI_{F}/dt = -200 \mbox{ A/}\mu s, \\ \mbox{V}_{R} = 600 \mbox{ V, } T_{j} = 125^{\circ} \mbox{ C} \\ \end{array} $			1.5		
t _{fr}	Forward recovery time	$ I_F = 30 \ A \qquad dI_F/dt = 100 \ A/\mu s \\ V_{FR} = 1.5 \ x \ V_{Fmax}, \ T_j = 25^\circ \ C $			550	ns
V _{FP}	Forward recovery voltage	$I_F = 30 \text{ A}, \text{ d}I_F/\text{d}t = 100 \text{ A}/\mu\text{s},$ $T_j = 25^{\circ} \text{ C}$		6		V

Table 4.Dynamic characteristics

Figure 1. Conduction losses versus average current

Figure 2. Forward voltage drop versus forward current

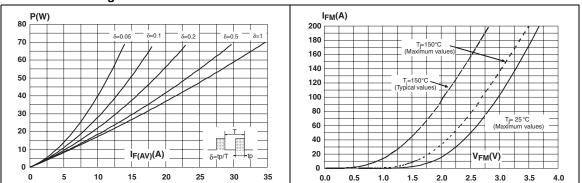




Figure 3. Relative variation of thermal impedance junction to case versus pulse duration

Figure 4. Peak reverse recovery current versus dl_F/dt (typical values)

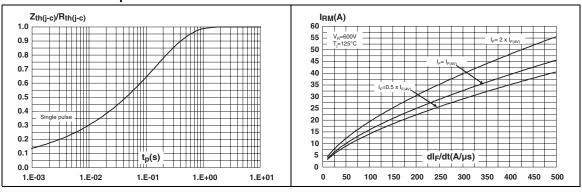


Figure 5. Reverse recovery time versus dl_F/dt (typical values)

Figure 6. Reverse recovery charges versus dl_F/dt (typical values)

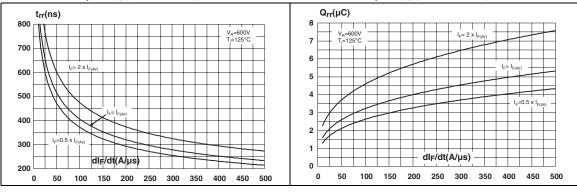
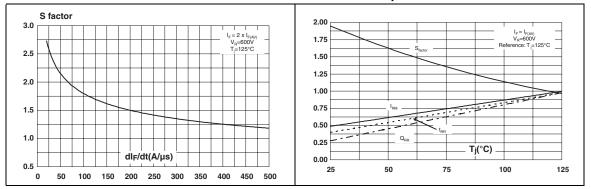


Figure 7. Softness factor versus dl_F/dt (typical values)

Figure 8. Relative variations of dynamic parameters versus junction temperature



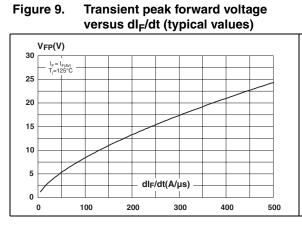


Figure 10. Forward recovery time versus dl_F/dt (typical values)

Characteristics

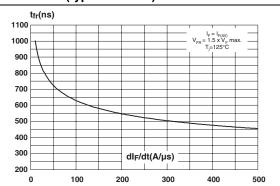
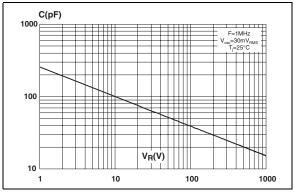


Table 5.Junction capacitance versus
reverse voltage applied (typical
values)



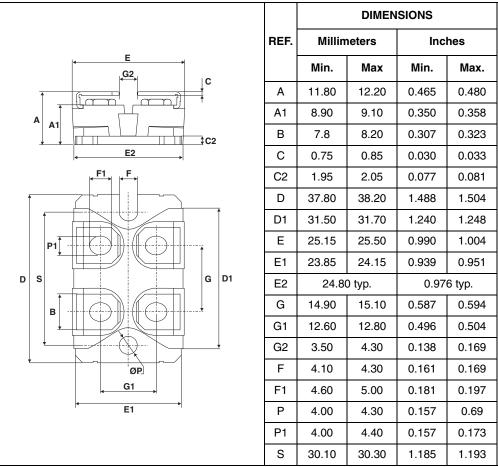
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2 Package information

Epoxy meets UL94, V0

Cooling method: by conduction (C)





In order to meet environmental requirements, ST offers these devices in ECOPACK® packages. These packages have a lead-free second level interconnect. The category of second level interconnect is marked on the package and on the inner box label, in compliance with JEDEC Standard JESD97. The maximum ratings related to soldering conditions are also marked on the inner box label. ECOPACK is an ST trademark. ECOPACK specifications are available at: www.st.com.

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3 Ordering information

Part Number	Marking	Package	Weight	Base qty	Delivery mode
STTH6112TV1	STTH6112TV1	ISOTOP	27 g	10	Tube
STTH6112TV2	STTH6112TV2	ISOTOP	27 g	10	Tube

4 Revision history

Date	Revision	Description of Changes
02-Mar-2006	1	First issue.



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